

**Search Notes**

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10/821,527

Examiner

Hieu P. Nguyen

Applicant(s)/Patent under  
Reexamination

YANG ET AL.

Art Unit

2817

**SEARCHED**

Class	Subclass	Date	Examiner
330	10	1/23/2006	HN
330	207A	1/23/2006	HN
330	251	1/23/2006	HN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
US-PGPUB		6/29/2006	HN

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST UPDATE SEARCH SEE PRINT OUT	6/29/2006	HN